

CHONGQING CLOUDCHILD TECHNOLOGY CO.,LTD

DFN14*12 Plastic-Encapsulate MOSFETS

CCM75N4-6A

Full bridge N Channel MOSFET

$V_{(BR)DSS}$	$R_{DS(on)}TYP$	I _D
	3.9mΩ@10V	
40 V	5.0mΩ@4.5V	75A

DESCRIPTION

The CCM75N4-6A provides excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

FEATURE

- Split Gate Trench Technology
- Low RDS(ON)
- Low Gate Charge
- Low Gate Resistance
- AEC Q101 qualified

APPLICATION

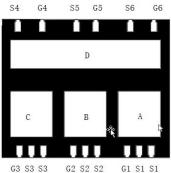
- motor control
- Full bridge module

MARKING

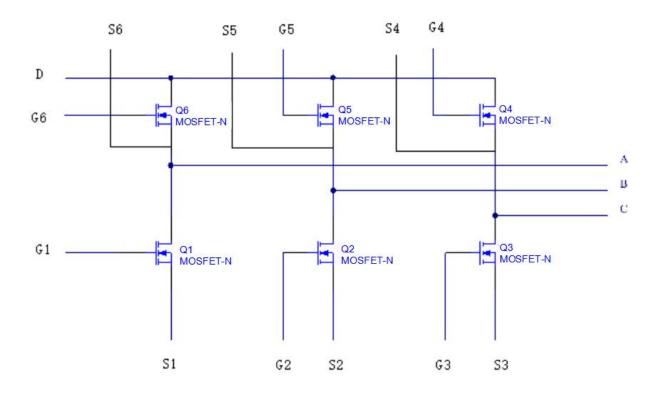


CCM75N4-6A =Part No. XXXXXXX = Code





EQUIVALENT CIRCUIT



Pin Definition

Number	Pin Definition	Remark	Number	Pin Definition	Remark
1	S1	Lower bridge u phase source	11	G4	Upper bridge w gate
2	S1	Lower bridge u phase source	12	S5	Upper Bridge v phase source collection
3	G1	Lower bridge u phase gate	13	G5	Upper bridge v gate
4	S2	Lower bridge v phase source	14	S6	Upper Bridge u phase source collection
5	S2	Lower bridge v phase source	15	G6	Upper bridge u gate
6	G2	Lower bridge v phase gate	PAD 1	D	DC Input
7	S3	Lower bridge w phase source	PAD 2	А	A phase output
8	S3	Lower bridge w phase source	PAD 3	В	B phase output
9	G3	Lower bridge w phase gate	PAD 4	С	C phase output
10	S4	Upper Bridge w phase source collection			

ABSOLUTE MAXIMUM RATINGS (T_a=25C unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	40	V
Gate-Source Voltage	V _{GS}	±20	V
Continuous Drain Current ¹	ID	75	Α
Pulsed Drain Current ²	IDM	300	Α
Single Pulsed Avalanche Energy ³	EAS	240	mJ
Total Power Dissipation	P _D	83	W
Thermal Resistance from Junction to Case ¹	R _{thJC}	1.8	°C/W
Junction Temperature	TJ	175	℃
Storage Temperature	Tstg	-55~+175	℃
Soldering Temperature , for 10S(1.6mm from case)	-	260	$^{\circ}$

Notes:

1. The maximum current rating is limited by package. And device mounted on a large heatsink.

2.Pulse Test : Pulse Width ≤ 10μ s, duty cycle ≤ 1%.

3.EAS condition: VDD = 20V,VGS = 10V, L = 0.5mH, RG = 25 Ω , Ias=31A, Starting TJ = 25 $^{\circ}$ $^{\circ}$ C.

MOSFET ELECTRICAL CHARACTERISTICS

TC=25℃ unless otherwise specified

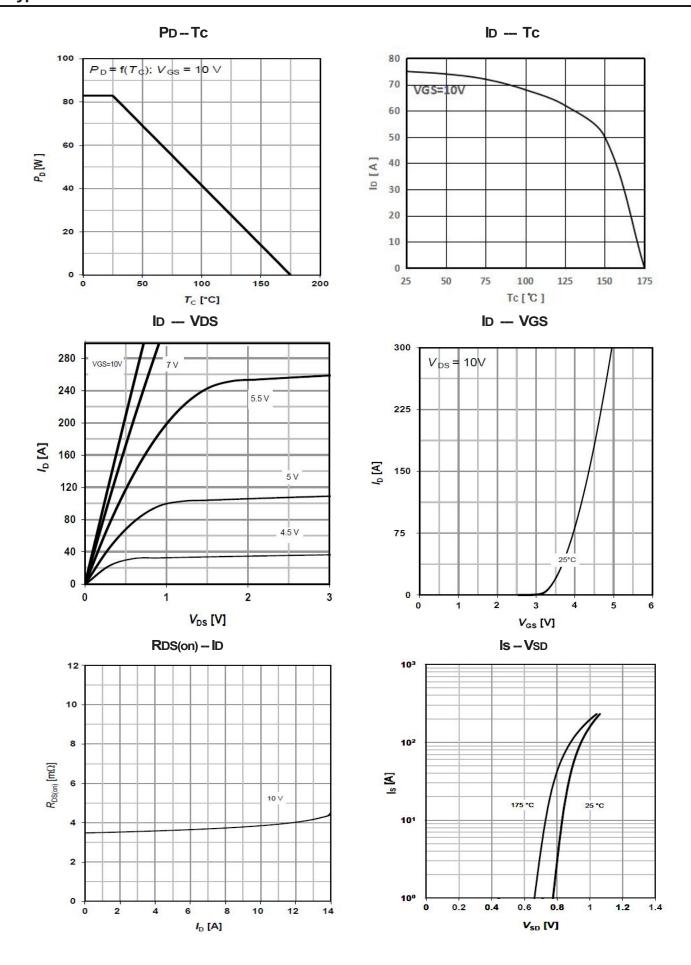
Parameter	Symbol	Test Condition	Min	Туре	Max	Unit
Off Characteristics						
Drain - Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0V, I _D = 250μA	40			V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 40V, V _{GS} = 0V			1	μΑ
Gate - Body Leakage Current	I _{GSS}	$V_{GS} = \pm 20V, V_{DS} = 0V$			±100	nA
On Characteristics ³	•					
Gate Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.0	1.7	3.0	V
Drain-source On-resistance	D	V _{GS} = 10V, I _D = 10A		3.9	6.2	mΩ
Drain-source On-resistance	R _{DS(on)}	V _{GS} = 4.5V, I _D = 10A		5.0	7.2	
Forward Transconductance	g Fs	V _{DS} = 10V, I _D = 10A		70		S
Dynamic Characteristics	•			•		
Input Capacitance	C _{iss}			6800		
Output Capacitance	Coss	$V_{DS} = 25V, V_{GS} = 0V, f = 1MHz$		408		pF
Reverse Transfer Capacitance	Crss	1		331		
Gate Resistance	Rg	$V_{DS} = 0V, V_{GS} = 0V, f = 1MHz$		1.5		Ω
Switching Characteristics		•		•		
Total Gate Charge	Qg			31		
Gate-source Charge	Q_{gs}	$V_{DD} = 20V, V_{GS} = 10V, I_D = 20A$		6		nC
Gate-drain Charge	Q_{gd}]		3.8		
Turn-on Delay Time	t _{d(on)}			7		
Turn-on Rise Time	t _r	$V_{DD} = 20V, V_{GS} = 10V, R_L = 1\Omega$,		2.8		ns
Turn-off Delay Ttime	t _{d(off)}	$R_G = 3\Omega$		24		115
Turn-off Fall Time	t _f	1		3.9		
Source - Drain Diode Characteristics	•			•		
Diode Forward Voltage ³	V _{SD}	V _{GS} = 0V, I _S = 10A			1.2	V
Continuous drain-source diode forward Current ¹	ls	-			75	Α
Pulsed drain-source diode forward current ²	I _{SM}	-			300	Α
Reverse recovery time	Trr	Ic-104 dl/dt-1004/va		26		ns
Reverse recovery charge	Qrr	IF=10A,dI/dt=100A/us		28		nC

Notes:

 $^{1.}T_{\text{C}}\text{=}25^{\circ}\text{C}$ Limited only by maximum $\,$ temperature allowed.

^{2.}P_W≤10µs, Duty cycle≤1%.

^{3.} Pulse Test : Pulse Width ≤ 300µs, duty cycle ≤ 2%.



T, [°C]

Q_{gate} [nC]

Typ.capacitances

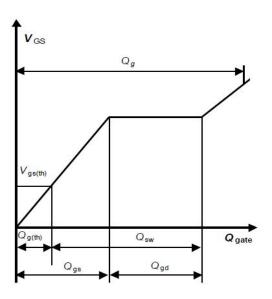
10000 Vgs=0,f=1MHz Ciss 1000 Coss 1000 Crss 1000

10

VDS[V]

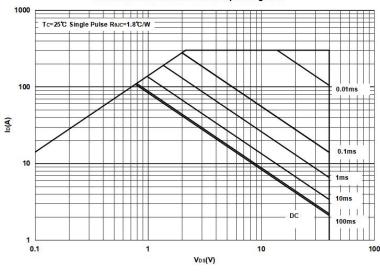
10

Gate charge waveforms

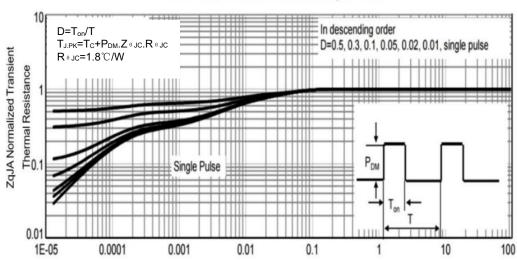


Maximum Forward Biased Safe Operating Area

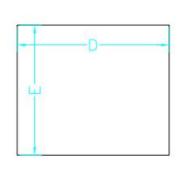
30

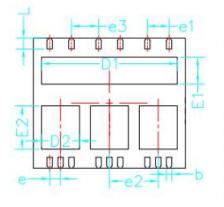


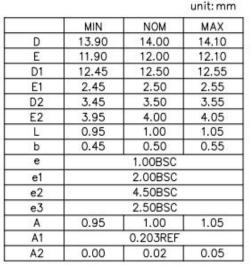
Normalized Thermal Transient Impedance



DFN14*12 Package Outline Dimensions

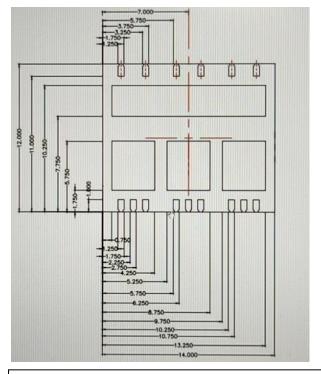








DFN14*12 Suggested Pad Layout



Note:

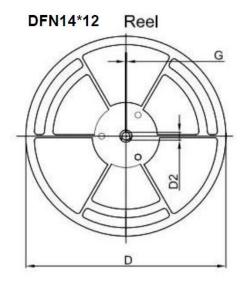
- 1. Controlling dimension: in millimeters.
- 2. General tolerance:0.5mm.
- 3. The pad layout is for reference purposes only.

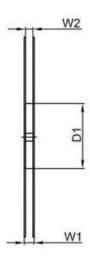
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DFN14*12 Tape and Reel





			Dimensio	ns are in millime	ter	
Reel Option	D	D1	D2	G	W1	W2
13"Dla	Ø330.00	100,00	13.00	1.90	28.40	24.00

REEL	Reel Size	Box	Box Size(mm)	Carton	Carton Size(mm)
2,000 pcs	13 inch	4,000 pcs	340×336×29	20,000 pcs	353×346×365

Rev#	revise content
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